

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	302	(438/117).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/08 18:49
L2	0	<i>L1 and oxide adj ring</i>	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L3	0	<i>L1 and oxide near2 ring</i>	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L4	0	<i>L1 and gurad near2 ring</i>	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L5	3	<i>L1 and guard near2 ring</i>	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L6	2	"20050127495".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L7	8	("5776826" "6107161" "6509622" "6596562").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L8	4	("5637862" "6168311" "6399463").PN. OR ("6596562").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/08 18:49
L9	1148	(438/113).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/08 18:49

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L10	299	(438/114).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/08 18:49
L11	1305	L9 or L10	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L12	9	L11 and sealing near 2 ring	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L13	587	L11 and dicing	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L14	281	L11 and crack\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L15	0	("2003/0124771").URPN.	USPAT	OR	ON	2006/12/08 18:49
L16	0	("2003/0124771").URPN.	USPAT	OR	ON	2006/12/08 18:49
L17	1	"6596562".PN.	USPAT	OR	ON	2006/12/08 18:49
L18	2	"6596562".PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L19	3	("5637862" "6168311" "6399463").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/08 18:49
L20	3	"6838299"	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/08 18:49
L21	1	"6838299".pn.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/08 18:49
L22	5	("5024970" "6306731" "6365958").PN. OR ("6838299"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/08 18:49

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L23	23	("5530280" "5763936" "5831330" "5834829" "5936260" "6111419").PN. OR ("6365958").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/08 18:49
L24	5	scribe with seal with oxide	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/08 18:49
L25	5	scribe with seal with oxide	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L26	7	scribe and seal and oxide	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L27	9	dicing with seal with oxide	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L28	1292	via with oxide with copper	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L29	28	oxide near2 ring and ((sawing dicing cutting) with wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L30	84	guard with ring with insulating with made	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L31	48	andujar.xp.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L32	2	"6365958".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49

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L33	18	<i>USG with oxide with silicon adj oxide same interconnection</i>	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L34	8	<i>USG with oxide with silicon adj oxide same interconnection</i>	USPAT	OR	ON	2006/12/08 18:49
L35	2	"6992392".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L36	0	<i>L35 and glass with "22"</i>	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L37	0	<i>L35 and USG with "22"</i>	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L38	43	<i>USG with stability</i>	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L39	3	<i>USG with oxide with improve with silicon adj oxide</i>	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L40	5	<i>USG with oxide with desirable with silicon adj oxide</i>	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L41	2	<i>USG with enhanced with structural with stability</i>	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49

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L42	55	USG with oxide with silicon adj oxide and via with trench	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L43	417	USG with oxide with silicon adj oxide	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L44	0	USG with oxide with silicon adj oxide and via with trench	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L45	0	USG with oxide with better with silicon adj oxide	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L46	17	USG with oxide with more with silicon adj oxide	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L47	1	L35 and oxide with "22"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L48	417	USG with oxide with silicon adj oxide	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L49	4	USG with structural with stability	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L50	0	L35 and sog with "22"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L51	1	2005-275355.NRAN.	DERWENT	OR	ON	2006/12/08 18:49

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L52	1432	crack\$ and multi near1 level	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L53	17	crack\$ and multi near1 level	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L54	66	crack\$ and wir\$3 and (IC semiconductor integrated near1 circuit die chip silicon) and oxide and pad	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L55	516	crack\$ and wir\$3 and (IC semiconductor integrated near1 circuit die chip silicon) and oxide	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L56	5255	crack\$ and wir\$3 and (IC semiconductor integrated near1 circuit die chip silicon)	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 18:49
L57	0	("crack\$3 and multi\$level").PN.	FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/08 18:49
L58	95	(oxide and ring and trench).clm.	US-PGPUB	OR	ON	2006/12/08 19:10
L59	0	(oxide and ring and trench and gurad near2 ring).clm.	US-PGPUB	OR	ON	2006/12/08 19:10
L60	0	(oxide and trench and gurad near2 ring).clm.	US-PGPUB	OR	ON	2006/12/08 19:10
L61	35	(oxide and trench and guard near2 ring).clm.	US-PGPUB	OR	ON	2006/12/08 19:15
L62	1882	(257/700).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/08 19:15
L63	1	62 and oxide with ring with trench	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 19:16
L64	985	(438/629).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/08 19:15

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L65	1	64 and oxide with ring with trench	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 19:16
L66	4	64 and ring with trench	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/08 19:16